Ferroelectric co-crystalline polymers

Christophe Daniel, Claudia Rufolo, Fabrizio Bobba, Alessandro Scarfato, Anna Maria Cucolo and Gaetano Guerra

Supporting information

In Figure S1 are reported the topographic and PFM images before and after poling of a s-PS film exhibiting the co-crystalline phase with NA obtained before and during poling.

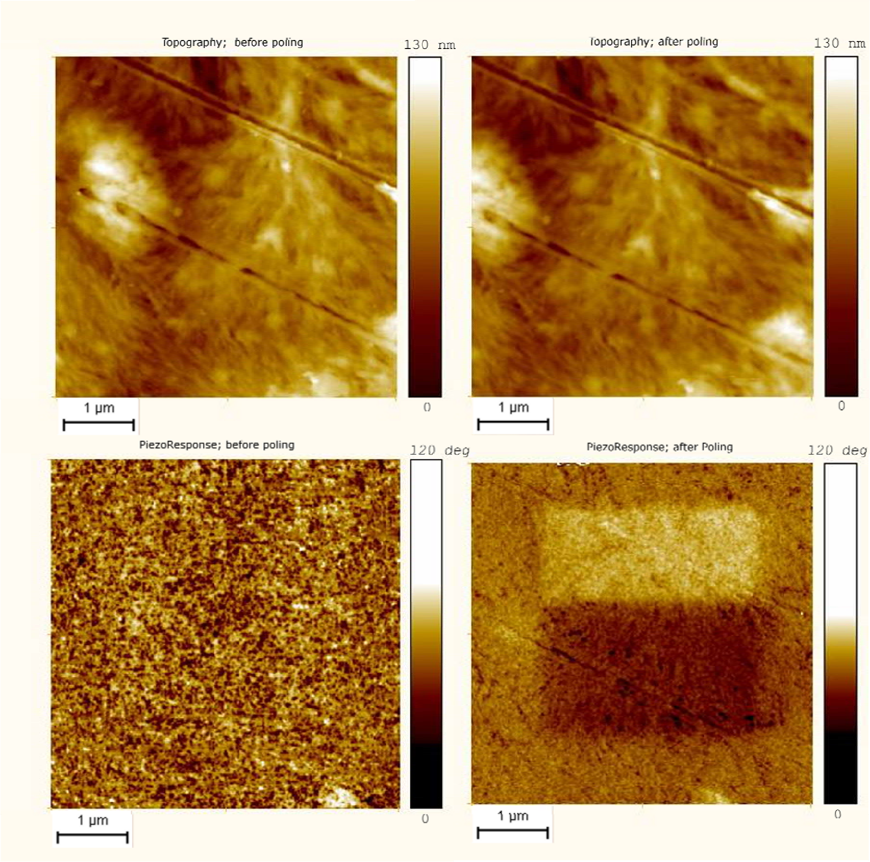

Fig. S1. Topographic (upper images) and PFM images (lower images) of a s-PS film exhibiting the co-crystalline phase with NA obtained before (left images) and during poling (right images).

The topographic images reported in Figure S1 show that the morphological structure of the sample is not modified after poling while the roughness analysis of the topographic, just before and during the poling procedure, gives similar results. The measured peak to peak roughness was 130 nm and 117 nm with an average roughness of 13 nm and 11.8 nm, before poling and during poling, respectively.

These result indicate that the poling with the AFM tip does not modify the surface morphology of the sample during the SPFM measurements.